Search Notes



Application/Control No.	Applicant(s)/Patent under Reexamination
10/598 537	JEONG BYEONG HEE

3644

10/598,53 Examiner Art Unit

Trinh T. Nguyen

SEARCHED				
Class	Subclass	Date	Examiner	
47	41.01 41.12 41.13 41.14 41.15	6/5/2008	TTN	
	62R 62A 62N			
	79 48.5 80			
	81			

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
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nventor name search was performed.	6/5/2008	TTN		